# 2SK3927-01L,S,SJ

## N-CHANNEL SILICON POWER MOSFET

## FUJI POWER MOSFET
## Super FAP-G Series

### ■ Features

**High speed switching** **Low on-resistance**
**No secondary breakdown** **Low driving power**
**Avalanche-proof**

### ■ Applications

**Switching regulators** **DC-DC converters**
**UPS (Uninterruptible Power Supply)**

### ■ Outline Drawings (mm) 200406

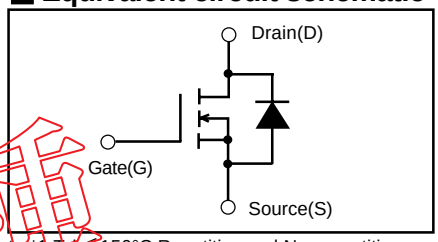
See to P4

### ■ Maximum ratings and characteristic

● **Absolute maximum ratings**
**(Tc=25°C unless otherwise specified)**

| Item | Symbol | Ratings | Unit | Remarks |
|---|---|---|---|---|
| Drain-source voltage | $V_{DS}$ | 250 | V | |
| | $V_{DSX}$ | 220 | V | $V_{GS}$=-30V |
| Continuous Drain Current | $I_D$ | 34 | A | |
| Pulsed Drain Current | $I_{D(puls)}$ | ±136 | A | |
| Gate-Source Voltage | $V_{GS}$ | ±30 | V | |
| Maximum Avalanche current | $I_{AR}$ | 34 | A | Note *1 |
| Non-Repetitive Maximum Avalanche Energy | $E_{AS}$ | 665.7 | mJ | Note *2 |
| Repetitive Maximum Avalanche Energy | $E_{AR}$ | 27 | mJ | Note *3 |
| Maximum Drain-Source dV/dt | dVDS/dt | 20 | kV/µs | $V_{DS}$≦250V |
| Peak Diode Recovery dV/dt | dV/dt | 5 | kV/µs | Note *4 |
| Peak Diode Recovery -di/dt | -di/dt | 100 | A/µs | Note *5 |
| Max. Power Dissipation | $P_D$ | 270 | W | Tc=25°C |
| | | 2.02 | | Ta=25°C |
| Operating and Storage Temperature range | $T_{ch}$ | +150 | °C | |
| | $T_{stg}$ | -55 to +150 | °C | |

### ■ Equivalent circuit schematic




Note *1:Tch≦150°C,Repetitive and Non-repetitive
Note *2:StartingTch=25°C,$I_{AS}$=14A,L=5.71mH,
$V_{CC}$=48V,$R_G$=50Ω
$E_{AS}$ limited by maximum channel temperature and Avalanche current.
See to the 'Avalanche Energy' graph
Note *3:Repetitive rating:Pulse width limited by maximum channel temperature.
See to the 'Transient Thermal impedance' graph.
Note *4:$I_F$≦-$I_D$, -di/dt=100A/µs,$V_{CC}$≦$BV_{DSS}$,Tch≦150°C
Note *5:$I_F$≦-$I_D$, dv/dt=5kV/µs,$V_{CC}$≦$BV_{DSS}$,Tch≦150°C



● **Electrical characteristics ($T_C$ =25°C unless otherwise specified)**

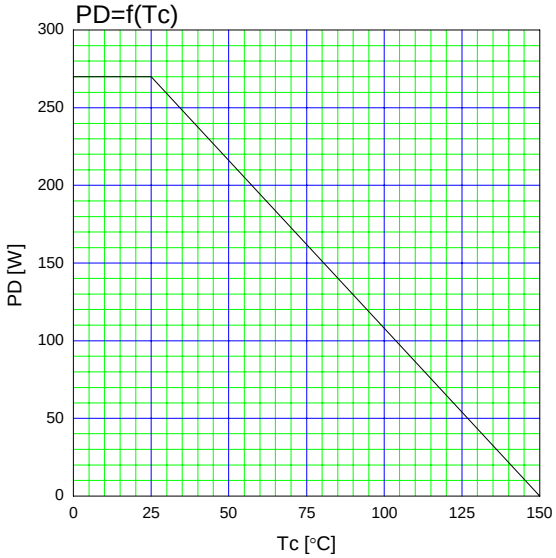
| Item | Symbol | Test Conditions | | Min. | Typ. | Max. | Units |
|---|---|---|---|---|---|---|---|
| Drain-Source Breakdown Voltage | $BV_{DSS}$ | $I_D$= 250µA $V_{GS}$=0V | | 250 | | | V |
| Gate Threshold Voltage | $V_{GS(th)}$ | $I_D$= 250µA $V_{DS}$=$V_{GS}$ | | 3.0 | | 5.0 | V |
| Zero Gate Voltage Drain Current | $I_{DSS}$ | $V_{DS}$=250V $V_{GS}$=0V | Tch=25°C | | | 25 | µA |
| | | $V_{DS}$=200V $V_{GS}$=0V | Tch=125°C | | | 2.0 | mA |
| Gate-Source Leakage Current | $I_{GSS}$ | $V_{GS}$=±30V $V_{DS}$=0V | | | | 100 | nA |
| Drain-Source On-State Resistance | $R_{DS(on)}$ | $I_D$=17A $V_{GS}$=10V | | | 85 | 110 | mΩ |
| Forward Transconductance | $g_{fs}$ | $I_D$=17A $V_{DS}$=25V | | 13 | 26 | | S |
| Input Capacitance | Ciss | $V_{DS}$=75V | | | 1850 | 2800 | pF |
| Output Capacitance | Coss | $V_{GS}$=0V | | | 220 | 330 | |
| Reverse Transfer Capacitance | Crss | f=1MH | | | 21 | 32 | |
| Turn-On Time $t_{on}$ | td(on) | $V_{CC}$=48V $I_D$=17A | | | 20 | 30 | ns |
| | tr | $V_{GS}$=10V | | | 19 | 29 | |
| Turn-Off Time $t_{off}$ | td(off) | $R_{GS}$=10Ω | | | 56 | 85 | |
| | tf | | | | 19 | 29 | |
| Total Gate Charge | $Q_G$ | $V_{CC}$=125V | | | 56 | 85 | nC |
| Gate-Source Charge | $Q_{GS}$ | $I_D$=34A | | | 20 | 30 | |
| Gate-Drain Charge | $Q_{GD}$ | $V_{GS}$=10V | | | 19 | 29 | |
| Diode forward on-voltage | $V_{SD}$ | $I_F$=34A $V_{GS}$=0V Tch=25°C | | | 1.00 | 1.50 | V |
| Reverse recovery time | trr | $I_F$=34A $V_{GS}$=0V | | | 140 | 250 | ns |
| Reverse recovery charge | Qrr | -di/dt=100A/µs Tch=25°C | | | 0.5 | 1.25 | µC |

● **Thermal characteristics**

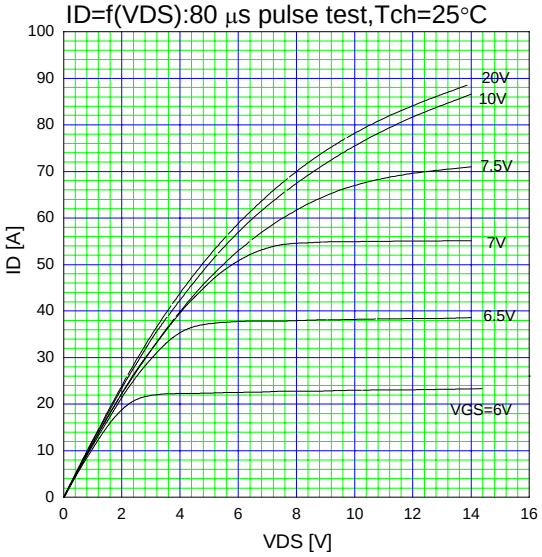
| Item | Symbol | Test Conditions | Min. | Typ. | Max. | Units |
|---|---|---|---|---|---|---|
| Thermal resistance | $R_{th(ch-c)}$ | channel to case | | | 0.463 | °C/W |
| | $R_{th(ch-a)}$ | channel to ambient | | | 75 | °C/W |

## Characteristics

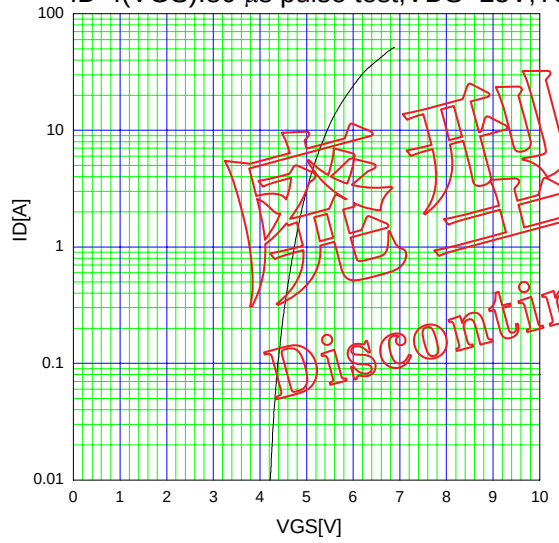
Allowable Power Dissipation
PD=f(Tc)



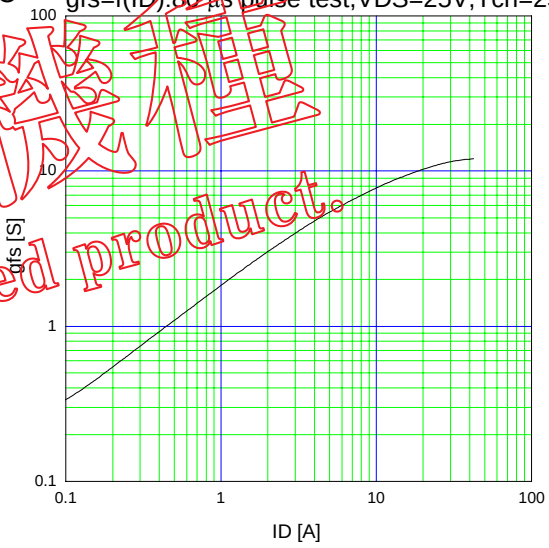

Typical Output Characteristics
ID=f(VDS):80 μs pulse test,Tch=25°C




Typical Transfer Characteristic
ID=f(VGS):80 μs pulse test,VDS=25V,Tch=25°C

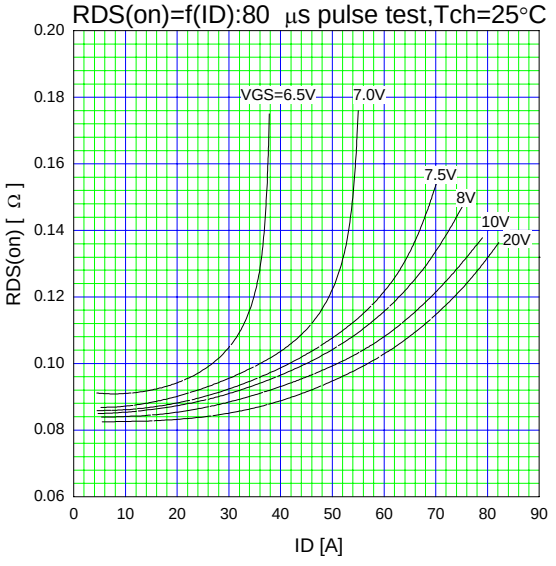



Typical Transconductance
gfs=f(ID):80 μs pulse test,VDS=25V,Tch=25°C

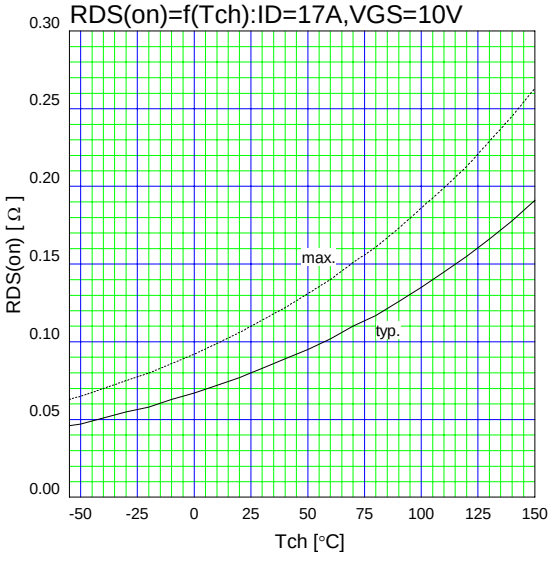




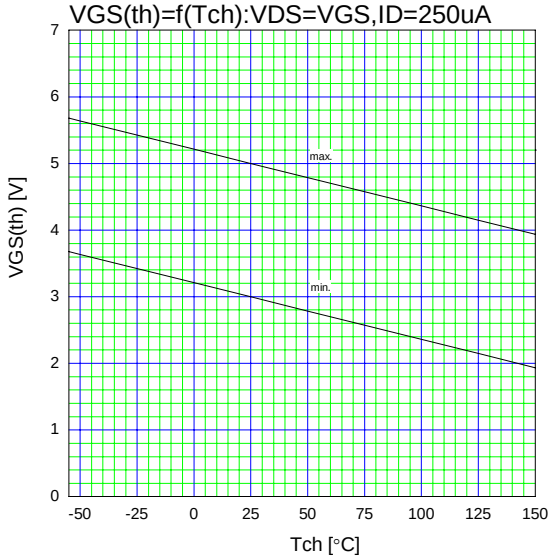

Typical Drain-Source on-state Resistance
RDS(on)=f(ID):80 μs pulse test,Tch=25°C



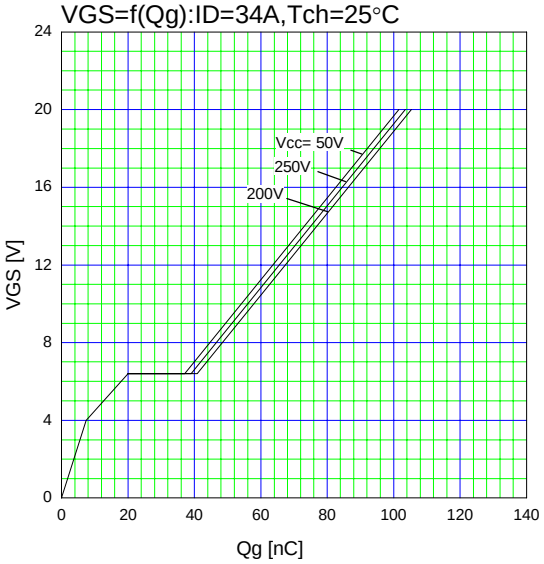

Drain-Source On-state Resistance
RDS(on)=f(Tch):ID=17A,VGS=10V



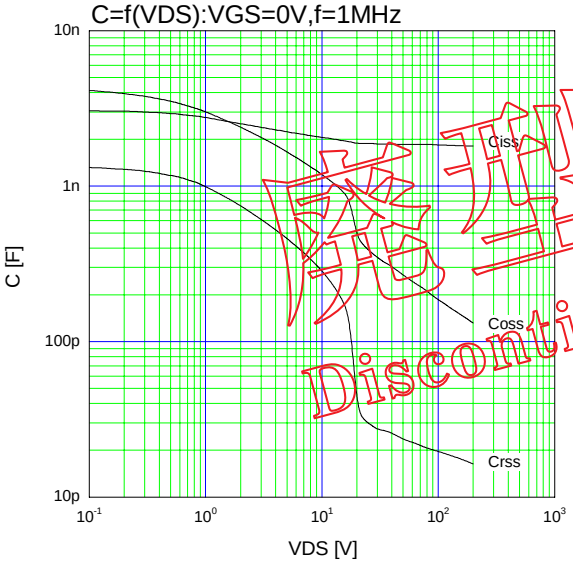
Gate Threshold Voltage vs. Tch
VGS(th)=f(Tch):VDS=VGS,ID=250uA



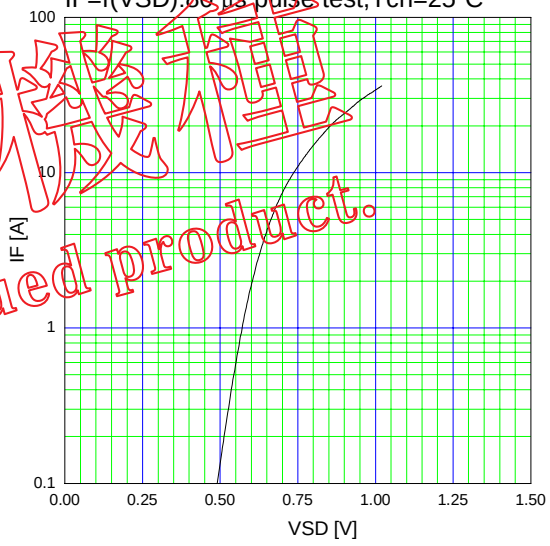

Typical Gate Charge Characteristics
VGS=f(Qg):ID=34A,Tch=25°C




Typical Capacitance
C=f(VDS):VGS=0V,f=1MHz

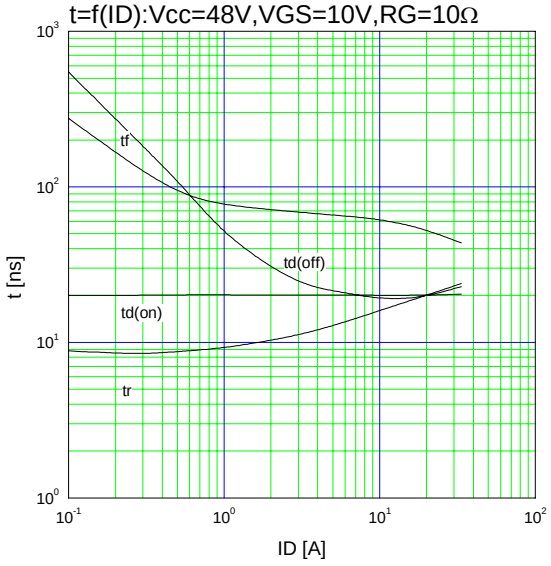



Typical Forward Characteristics of Reverse Diode
IF=f(VSD):80 μs pulse test,Tch=25°C

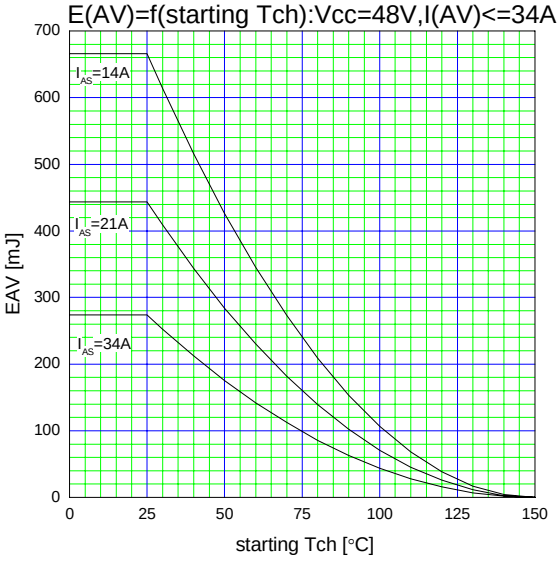




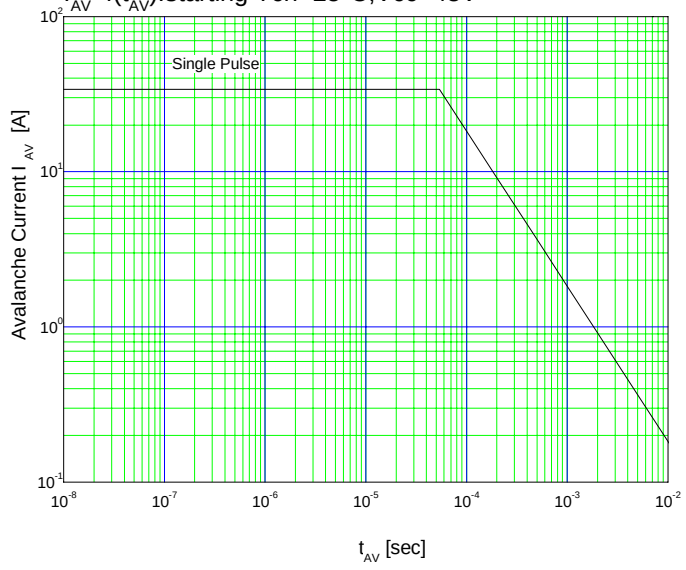

Typical Switching Characteristics vs. ID
t=f(ID):Vcc=48V,VGS=10V,RG=10Ω



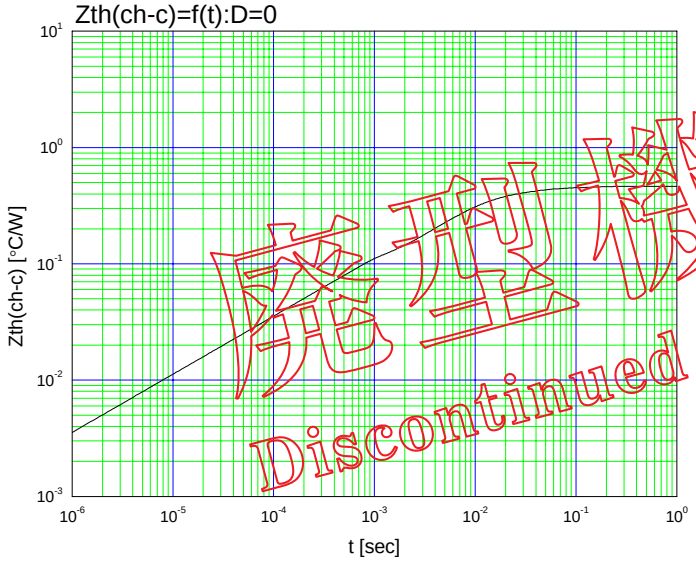

Maximum Avalanche Energy vs. starting Tch
E(AV)=f(starting Tch):Vcc=48V,I(AV)<=34A



Maximum Avalanche Current Pulsewidth
$I_{AV}$=f($t_{AV}$):starting Tch=25°C,Vcc=48V



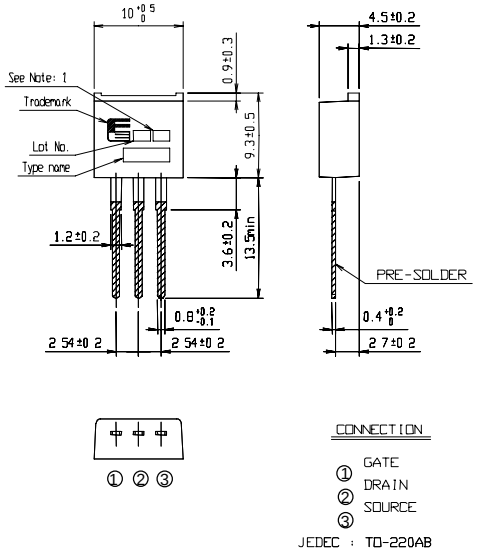

Transient Thermal Impedance
Zth(ch-c)=f(t):D=0



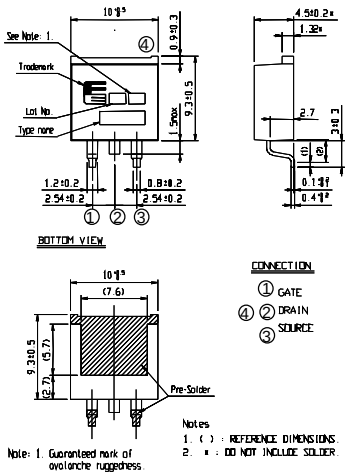



## ■ Outline Drawings (mm)

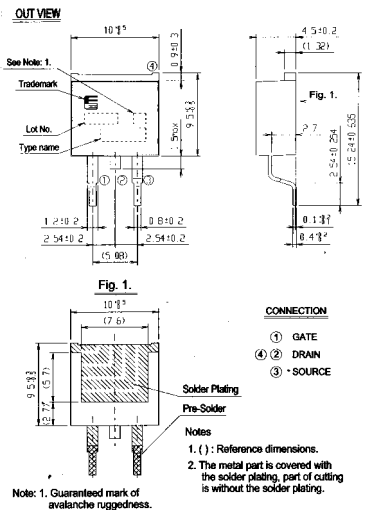
Type(L)




Type(S)




Type(SJ)




http://www.fujielectric.co.jp/fdt/scd/